

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Patent Application of  
MARSHALL et al.

Serial No. 09/923,341

Filed: August 8, 2001

For: PHOTODETECTOR CIRCUIT



Atty. Ref.: 124-880

Group: 2815

Examiner: Joseph Nguyen

\* \* \* \* \*

April 16, 2003

Assistant Commissioner for Patents  
Washington, DC 20231

Sir:

**INFORMATION DISCLOSURE STATEMENT**

As suggested by 37 C.F.R. 1.97, the undersigned attorney brings to the attention of the Patent and Trademark Office the reference listed on the attached form PTO-1449, a copy of each of which is enclosed. This is not to be construed as a representation that a search has been made or that no better prior art exists, or that a reference is relevant merely because cited.

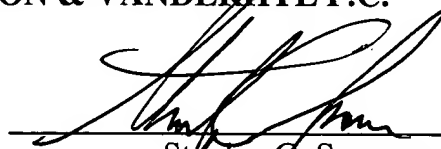
The Examiner is requested to initial the attached form PTO-1449 and to return a copy of the initialed document to the undersigned as an indication that the attached reference has been considered and made of record.

Pursuant to Rule 37 C.F.R. §1.97(c), a fee of \$180.00 as specified in Rule 17(p) is attached. If there is any shortage in the fee, please charge the deposit account of Nixon & Vanderhye, Account No. 14-1140.

Respectfully submitted,

**NIXON & VANDERHYE P.C.**

By:

  
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Serial No. 09/923,341

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INFORMATION DISCLOSURE  
CITATION

ATTY. DOCKET NO.

124-880

APPLICANT

MARSHALL et al.

FILING DATE

August 8, 2001

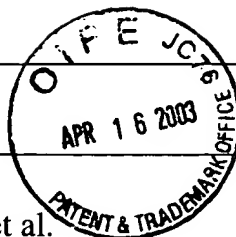
SERIAL NO.

09/923,341

GROUP

2815

(Use several sheets if necessary)



## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

## FOREIGN PATENT DOCUMENTS

DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO

## OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

	~ S.M. Sze VLSI Technology pp. 482-485
	~ Spinelli et al IEEE Transactions on Electron Devices, Vol. 44, No. 11, Nov. 1997 pp. 1931-1943 Physics and Numerical Simulation of Single Photon Avalanche Diodes
	~ Jackson et al Proc. IEEE 2001 Int. Conference on Microelectronic Test Structures, Vol. 14, March 2001 pp. 165-170 Process Monitoring and Defect Characterization of Single Photon Avalanche Diodes

\*Examiner

Date Considered

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.

Form PTO-FB-A820 (Also PTO-1449)